

1. Record Nr.	UNINA9910808190203321
Autore	Joy David C. <1943->
Titolo	Monte Carlo modeling for electron microscopy and microanalysis // David C. Joy
Pubbl/distr/stampa	New York, : Oxford University Press, 1995
ISBN	0-19-773242-9 1-280-53489-3 9786610534890 0-19-535846-5
Edizione	[1st ed.]
Descrizione fisica	1 online resource (225 p.)
Collana	Oxford series in optical and imaging sciences ; ; 9
Disciplina	502/.8/25
Soggetti	Electron microscopy - Computer simulation Electron probe microanalysis - Computer simulation Monte Carlo method
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Previously issued in print: 1995.
Nota di bibliografia	Includes bibliographical references.
Nota di contenuto	Contents; 1. An Introduction to Monte Carlo Methods; 2. Constructing a Simulation; 3. The Single Scattering Model; 4. The Plural Scattering Model; 5. The Practical Application of Monte Carlo Models; 6. Backscattered Electrons; 7. Charge Collection Microscopy and Cathodoluminescence; 8. Secondary Electrons and Imaging; 9. X-ray Production and Microanalysis; 10. What Next in Monte Carlo Simulations?; References; Index
Sommario/riassunto	1. Preface. 2. An Introduction to Monte Carlo Methods. 3. Constructing a Simulation. 4. The Single Scattering Model. 5. The Plural Scattering Model. 6. Practical Applications of Monte Carlo Models. 7. Backscattered Electrons. 8. Charge Collection and Cathodoluminescence. 9. Secondary Electrons and Imaging. 10. X-Ray Production and Micro-Analysis. 11. What Next in Monte Carlo Simulations?